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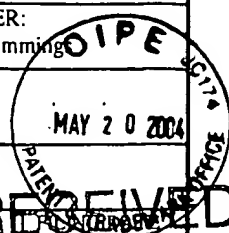
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INVENTOR'S NAME:
Jared ZERBE et al.

EXAMINER:
John P. Trimming

FILING DATE:
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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	TECHNOLOGY CENTER
ms	1.	3869580	03-04-1975	Ragsdale			
ms	2.	3909563	09-30-1975	Ghosh et al.			
ms	3.	4271514	06-02-1981	Parras et al.			
ms	4.	4727540	02-23-1988	Lacroix et al.			
ms	5.	5142495	08-25-1992	Canepa			
ms	6.	5197062	03-23-1993	Picklesimer			
ms	7.	5228042	07-13-1993	Gauthier et al.			
ms	8.	5258986	11-02-1993	Zerbe			
ms	9.	5265089	11-23-1993	Yonehara			
ms	10.	5383177	01-17-1995	Tateishi			
ms	11.	5392298	02-21-1995	Shinjo			
ms	12.	5412665	05-02-1995	Gruodis et al.			
ms	13.	5430736	07-04-1995	Takeoka et al.			
ms	14.	5444715	08-22-1995	Gruetzner et al.			
ms	15.	5473619	12-05-1995	Sakaguchi			
ms	16.	5485473	01-16-1996	Diebold et al.			
ms	17.	5490150	02-06-1996	Andrews et al.			
ms	18.	5519719	05-21-1996	Elpers et al.			
ms	19.	5675588	10-07-1997	Maruyama et al.			
ms	20.	5790523	08-04-1998	Ritchie, Jr. et al.			
ms	21.	5831996	11-03-1998	Abramovici et al.			
ms	22.	5841271	11-24-1998	Nakayama			
ms	23.	5875177	02-23-1999	Uriu et al.			
ms	24.	5938784	08-17-1999	Kim			
ms	25.	5999022	12-07-1999	Iwata et al.			
ms	26.	6061817	05-09-2000	Jones et al.			
ms	27.	6073263	06-06-2000	Arkin et al.			
ms	28.	6160790	12-12-2000	Bremer			
ms	29.	6201829	03-13-2001	Schneider			
ms	30.	6222380	04-24-2001	Gerowitz et al.			

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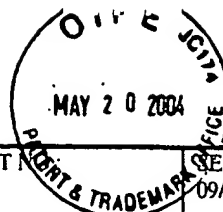
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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
JPZ	31.	20010034866	10-25-2001	Barry et al.			
JPZ	32.	6385236	05-07-2002	Chen			
JPZ	33.	20020059546	05-16-2002	Yonetoku			
JPZ	34.	20020059545	05-16-2002	Nakashima et al.			
JPZ	35.	20020073373	06-13-2002	Nakao et al.			
JPZ	36.	6407572	06-18-2002	Kanase et al.			
JPZ	37.	20020108079	08-08-2002	Takahashi			
JPZ	38.	6438159	08-20-2002	Uber et al.			
JPZ	39.	20020138800	09-26-2002	Kim et al.			
JPZ	40.	6473871	10-29-2002	Coyle et al.			
JPZ	41.	6477674	11-05-2002	Bates et al.			
JPZ	42.	20020178412	11-28-2002	Matsui			
JPZ	43.	20030065995	04-03-2003	Barrett			
JPZ	44.	20030070118	04-10-2003	Nakao et al.			
JPZ	45.	20030088818	05-08-2003	Manning			
JPZ	46.	6574758	06-03-2003	Eccles			
JPZ	47.	20030131297	07-10-2003	Fischel et al.			
JPZ	48.	6611928	08-26-2003	Fujioshi et al.			
JPZ	49.	6625764	09-23-2003	Dawson			
JPZ	50.	6684351	01-27-2004	Bendak et al.			
JPZ	51.	6684350	01-27-2004	Theodoras, II et al.			
JPZ	52.	6693881	02-17-2004	Huysmans et al.			
JPZ	53.	6694466	02-17-2004	Tsai et al.			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Country	Translation (Y/N)
		Office ³	Number ⁴	Kind Code ⁵ (if known)				
JPZ	54.		4-246921		Nishi	09-02-1992	JP	Y(Abstract)
JPZ	55.		0333942		Woodroffe	09-27-1989	EP	N
JPZ	56.		4-147071		Nakamura	05-20-1992	JP	Y(Abstract)

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